

### **Remarks**

Applicant thanks the Examiner for the careful examination of this application and the clear explanation of the rejections.

The amended title is clearly indicative of the invention to which the claims are directed.

The new claims "particularly point out and distinctly claim the subject matter the applicant regards as his invention."

New independent claim 35 defines an integrated circuit comprising a substrate of semiconductor material, pads formed on the semiconductor material, and functional circuits formed on the substrate and having functional output leads coupled to the pads.

Output buffer circuitry is formed on the substrate. For each functional output lead, the buffer circuitry has a buffer input lead connected to the functional output lead and a buffer output lead connected to a pad.

Test access port circuitry is formed on the substrate. The test access port circuitry has a test data input lead, a test data output lead, a test clock input lead, and a test mode select input lead, all connected to the pads.

Scan cells are formed on the substrate and are connected to the test access port circuitry, to the test data input lead, and to the test data output lead.

Test leads are formed on the substrate and are connected to the pads.

Scannable switch circuitry is formed on the substrate and is connected to the test access port circuitry, to the test data input lead, and to the test data output lead. The scannable switch circuitry selectively connects a buffer input lead and a buffer output lead to the test leads.

The present claims include test access port circuitry, scan cells, and scannable switch circuitry, which distinguish the present claims from the claims of US 6,199,182. This overcomes the double patenting rejection

The application is in allowable form and the claims distinguish over the cited references. Applicant respectfully requests reconsideration or further examination of this application.

Respectfully Submitted,

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